

## Supplementary Information for

### Size-Tunable Synthesis of Monolayer MoS<sub>2</sub> Nanoparticles and Their Applications in Non-Volatile Memory Devices

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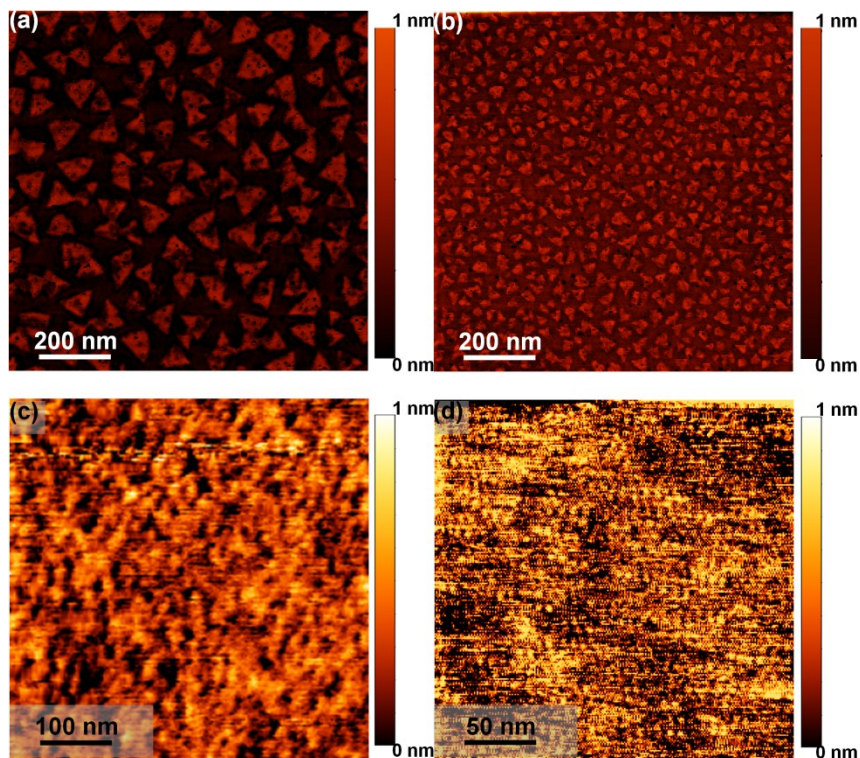
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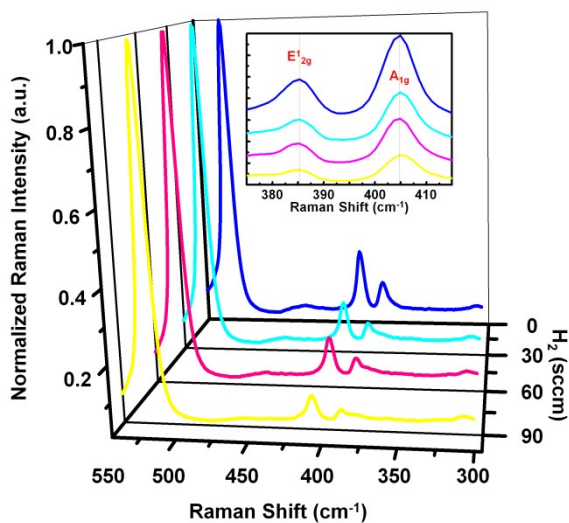
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**Surface Morphologies of the MoS<sub>2</sub> Nanoparticles:** The shapes and thicknesses of our CVD-grown size-tunable MoS<sub>2</sub> nanoparticles were characterized using AFM measurements. Supplementary Figure S1(a) shows the triangular MoS<sub>2</sub> nanoparticles grown under pure Ar gas. The largest nanoparticle size obtained under these conditions was 100 nm due to the typical sulfurization growth of molybdenum oxide and the high chemical potential of sulfur ( $\mu_s$ ). As hydrogen gas was injected during the growth of MoS<sub>2</sub> nanoparticles, the nanoparticle size decreased to 40 nm, 18 nm, or 6 nm, as shown in Supplementary Figure S1(b), S1(c), and S1(d) under the gas flow conditions: Ar 60 sccm–H<sub>2</sub> 30 sccm, Ar 60 sccm–H<sub>2</sub> 30 sccm, and H<sub>2</sub> 90 sccm, respectively. Most CVD-grown MoS<sub>2</sub> nanoparticles were 0.7–1 nm thick, comparable to the monolayer MoS<sub>2</sub> thickness. These measured values also agreed with the Raman spectra. Figure S2 shows the Raman spectra collected from the MoS<sub>2</sub> nanoparticles grown under different hydrogen gas flow rates. The normalized Raman spectrum from each nanoparticle displays two peaks at 385 cm<sup>-1</sup> (E<sub>2g</sub><sup>1</sup>: in-plane vibration of the Mo and S atoms) and 405 cm<sup>-1</sup> (A<sub>1g</sub><sup>1</sup>: out-of-plane vibration of the Mo and S atoms). These results agree well with reported values for exfoliated MoS<sub>2</sub><sup>1</sup>, suggesting that the MoS<sub>2</sub> nanoparticles have similar phonon–vibration characteristics even in crystals smaller than 10 nm in size. The difference between the wavenumbers of these two modes represents the number of MoS<sub>2</sub> layers present<sup>11</sup>. The difference between the E<sub>2g</sub><sup>1</sup> and A<sub>1g</sub><sup>1</sup> peak positions in the Raman spectra, shown in the inset of Figure S2, is 19.6 cm<sup>-1</sup>, in

agreement with previously reports of monolayer MoS<sub>2</sub><sup>1</sup>. The normalized Raman intensities of the two peaks decrease as the particle size decreases, due to a decrease in the phonon–vibration coupling strength within the small crystals<sup>2</sup>.

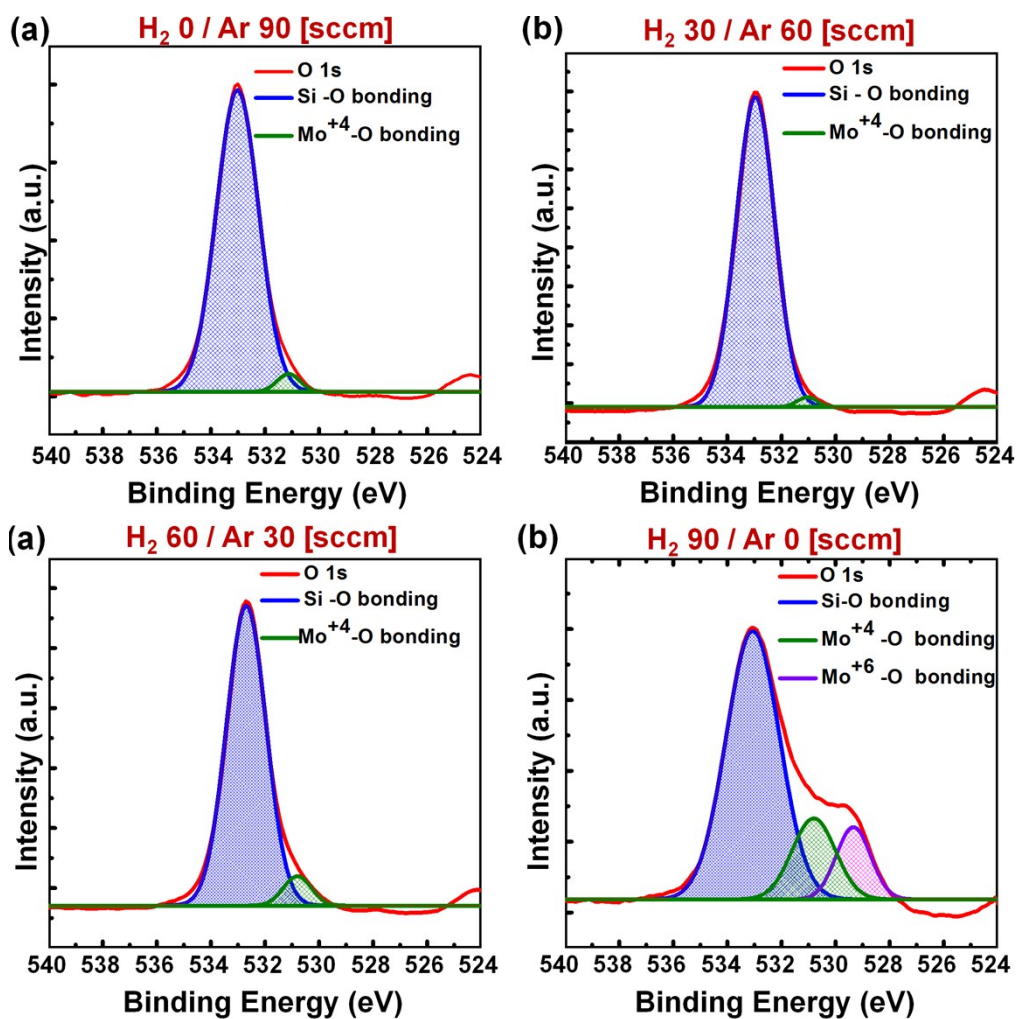


**Figure S1.** AFM measurements of the CVD-grown size-controlled MoS<sub>2</sub> nanoparticles grown under different conditions: (a) 50–70 nm MoS<sub>2</sub> nanoparticles grown in the absence of H<sub>2</sub>, (b) 30–60 nm MoS<sub>2</sub> nanoparticles grown under 30 sccm H<sub>2</sub>, (c) 10–30 nm MoS<sub>2</sub> nanoparticles grown under 60 sccm H<sub>2</sub>, (d) 2–10 nm MoS<sub>2</sub> nanoparticles grown under 90 sccm H<sub>2</sub>.



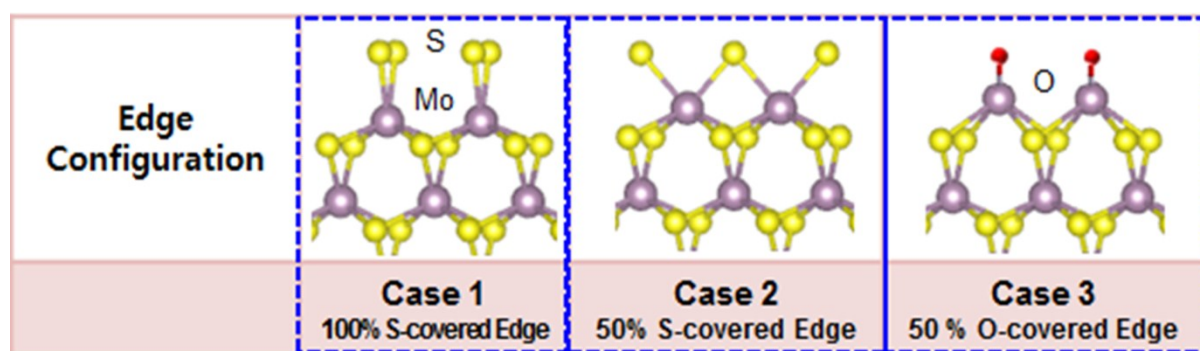
**Figure S2.** Raman spectra of the CVD-synthesized MoS<sub>2</sub> nanoparticles of different sizes, prepared under different H<sub>2</sub> gas flow rate conditions: full Raman spectra obtained from each sample, and enlarged Raman spectra (inset).

**Chemical Configuration of the Molybdenum Oxysulfide:** The chemical configurations of the MoS<sub>2</sub> nanoparticles were studied using XPS analysis. An abundance of hydrogen drove the oxidation of Mo atoms at the edge sites, as demonstrated by the Mo 3d and S 2p XPS spectra. Supplementary Figure S3 shows the deconvoluted O 1s XPS spectra obtained under the various H<sub>2</sub> flow rate conditions. The red curve indicates the full O 1s spectral shape, and the blue, green, and purple areas indicate Si-O bonding, Mo<sup>+6</sup>-O bonding, and Mo<sup>+4</sup>-O bonding. The binding energy of molybdenum oxide varied with the number of bonded oxygen atoms, yielded O 1s binding energies of 530.9 eV and 529.9 eV for MoO<sub>3</sub> and MoO<sub>2</sub>, respectively<sup>3</sup>. The O 1s binding energies in molybdenum oxysulfide (MoS<sub>x</sub>O<sub>3-x</sub> or MoS<sub>2x</sub>O<sub>x</sub>) were expected to decrease due to instabilities in the metal-oxysulfide states. The 0 sccm and 30 sccm H<sub>2</sub> flow rate conditions (Supplementary Figures S3 (a) and (b)) provided one small metal oxygen peak at 531 eV. This O 1s peak was reflective of MoS<sub>x</sub>O<sub>3-x</sub> on the edges of the MoS<sub>2</sub> nanoparticles. The peak corresponding to Mo<sup>+6</sup>-O bonding provided a very low contribution for two reasons: 1. the fraction of the relatively large MoS<sub>2</sub> nanoparticles corresponding to edges was low, and 2. sulfo-reduction under low H<sub>2</sub> concentrations was low. The peak intensity corresponding to Mo<sup>+6</sup>-O bonding increased due to large proportion of edges and the extensive oxidation at the edges of the MoS<sub>2</sub> nanoparticles under the H<sub>2</sub> flow rate condition (Supplementary Figures S3(c) and (d)). Supplementary Figure S3 (d) revealed an additional metal-oxide binding peak at 529.3 eV corresponding to the Mo<sup>+4</sup>-O bonding state in MoS<sub>2-x</sub>O<sub>x</sub>. The presence of Mo<sup>+4</sup>-O bonds indicated that the basal plane of the MoS<sub>2</sub> nanoparticles was oxidized due to extensive sulfur reduction under abundant H<sub>2</sub> conditions.



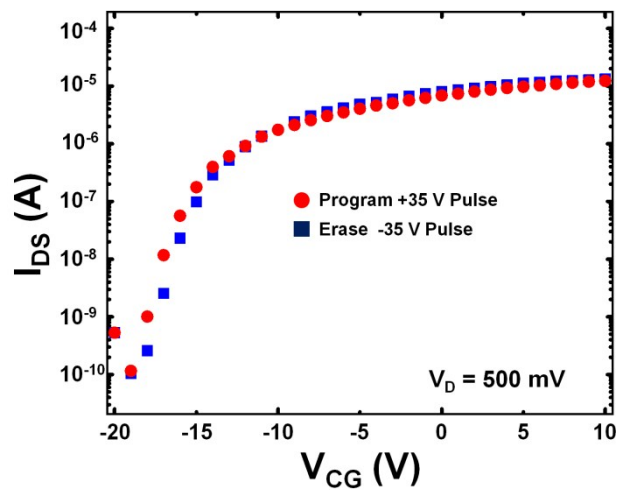
**Figure S3.** XPS O 1s spectra obtained under (a) 0 sccm, (b) 30 sccm, (c) 60 sccm, and (d) 90 sccm H<sub>2</sub> conditions.

**Edge Configuration in the DFT Models:** We studied the energy requirements for MoS<sub>2</sub> growth under different growth atmosphere conditions using density functional theory (DFT) calculation methods. Results from previous XPS and STM studies<sup>4-6</sup> were used to design various edge configurations under different hydrogen flow rate conditions. Case 1 shows that each edge Mo atoms were covered with S dimers. The Case 1 configuration was stable under an abundant S synthesis atmosphere. Case 2 revealed two Mo atoms at each edge connected to one S atom. This configuration was stable under S-deficient (or H<sub>2</sub>-abundant) conditions. Case 3 revealed that each Mo edge atom was connected to one O atom due to partial oxidization under abundant H<sub>2</sub> conditions.

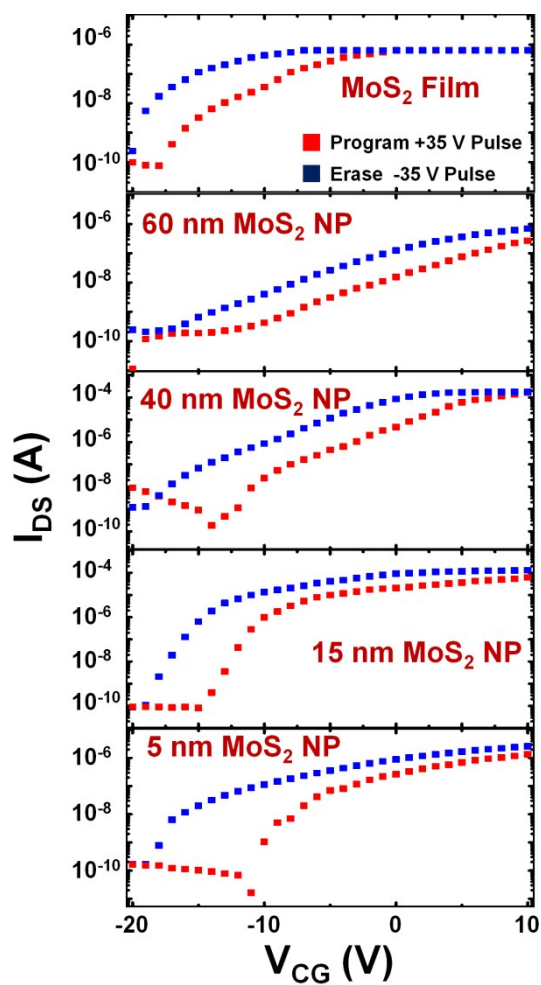


**Figure S4.** Edge configurations in the DFT models. Case 1: 100% S-covered edge; Case 2: 50% S-covered edge; Case 3: 50% O-covered edges. The purple, yellow, and red spheres indicate molybdenum, sulfur, and oxygen atoms, respectively.

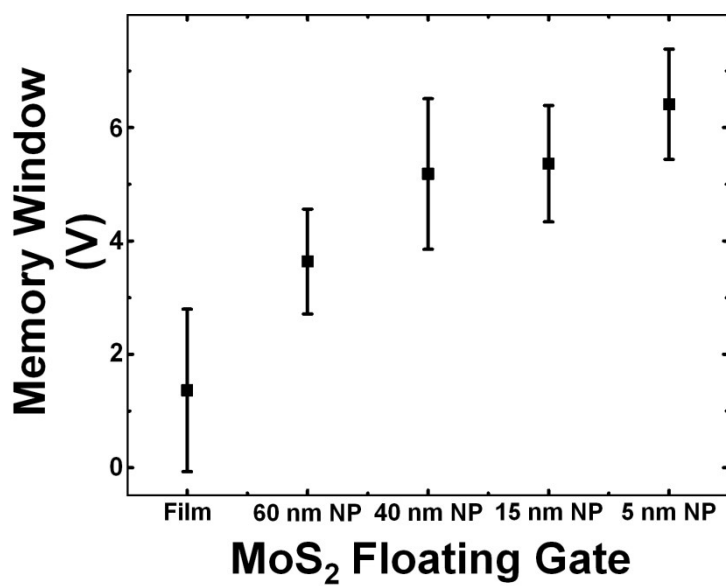
**Non-volatile memory prepared with a MoS<sub>2</sub> nanoparticle floating gate:** The  $I_{DS}$ - $V_{CG}$  transfer curves obtained from a device prepared without a floating gate revealed a negligible  $V_{th}$  shift between the program and erase states (Supplementary Figure S5). This device was fabricated using a few-layer MoS<sub>2</sub> channel that had been e-beam deposited onto a 10 nm SiO<sub>2</sub> layer supported by a 90 nm SiO<sub>2</sub>/Si substrate as a tunnel oxide. No other floating gate layers were present between the control oxide and the tunnel oxide. Supplementary Figure S6 shows the  $I_{DS}$  -  $V_{CG}$  transfer curves measured from memory devices prepared with 5 different floating gates. Each floating gate displayed several shifted  $V_{th}$  values in the range 2–8 V for the program and erase states. The memory device prepared with a 5 nm MoS<sub>2</sub> nanoparticle floating gate exhibited a large memory window due to the high fraction of edge states. The average memory windows were estimated from several fabricated memory devices prepared with 5 different floating gates (Supplementary Figure S7). The memory windows of each device depended on the MoS<sub>2</sub> nanoparticle size in the floating gate. The average memory window increased as the MoS<sub>2</sub> nanoparticle size decreased due to an increase in the presence of trap states from the MoS<sub>2</sub> edge as the MoS<sub>2</sub> nanoparticle size decreased.



**Figure S5.**  $I_{DS}$  -  $V_{CG}$  transfer characteristics measured from the MoS<sub>2</sub> back-gate FET prepared without a floating gate.



**Figure S6.**  $I_{DS} - V_{CG}$  transfer curves obtained from the memory devices prepared with various floating gates.



**Figure S7.** Average memory windows obtained from the different floating gates.

## References

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